

<b>Notice of References Cited</b>	Application/Control No. 10/583,865		Applicant(s)/Patent Under Reexamination FURUICHI ET AL.	
	Examiner KEVIN R. KRUER		Art Unit 1794	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,144,153	03-1979	Shikinami et al.	521/50.5
*	B	US-5,468,540	11-1995	Lu, Shih-Lai	428/156
*	C	US-2005/0069716	03-2005	Sasongko et al.	428/423.1
*	D	US-3,928,664	12-1975	Tarney et al.	427/322
*	E	US-4,422,907	12-1983	Birkmaier et al.	205/169
*	F	US-2,715,075	08-1955	WOLINSKI LEON E	428/516
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	10182851	07-1998	JP	Chen	--
	O	62019208	01-0987	JP	Hasegawa	--
	P	53071174	06-1978	JP	Takiron	--
	Q					
	R					
	S					
	I					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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